TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (MACHII π -MOSVI)

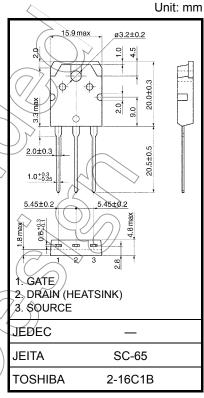
2SK3907

Switching Regulator Applications

- Small gate charge: Qg = 60 nC (typ.)
- Low drain-source ON resistance: $RDS(ON) = 0.18 \Omega \text{ (typ.)}$
- High forward transfer admittance: $|Y_{fs}| = 12 \text{ S (typ.)}$
- Low leakage current: $IDSS = 500 \mu A (VDS = 500 V)$
- Enhancement model: V_{th} = 2.0 to 4.0 V (V_{DS} = 10 V, I_{D} = 1 mA)

Absolute Maximum Ratings (Ta = 25°C)

Characteristic			Symbol	Rating	Unit	
Drain-source voltage		V _{DSS}	500	$(\checkmark \checkmark)$		
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)			V_{DGR}	500	V	
Gate-source voltage			V _{GSS}	±30	V	
Drain current	DC (No	te 1)	I _D	23	A	
	Pulse (No	te 1)	I _{DP}	92	A	
Drain power dissipation (Tc = 25°C)			PD	150	W	
Single pulse avalanche energy (Note 2)			EAS	552	(mJ	
Avalanche current			IAR	23	A	
Repetitive avalanche energy (Note 3)			EAR	15	mJ	
Channel temperature			((T _{ch}))	150	//°C	
Storage temperature range			T _{stg}	-55 to 150	°C	



Weight: 4.6 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

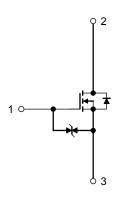
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Characteristic	Symbol	Max	Unit
Thermal resistance; channel to case	Rth (ch-c)	0.833	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	50	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C during use of the device.

Note 2: $V_{DD} = 90 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}$ (initial), L = 1.77 mH, $I_{AR} = 23 \text{ A}$, $R_G = 25 \Omega$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.

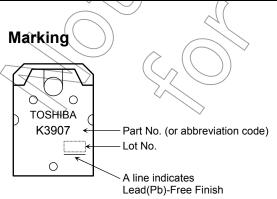


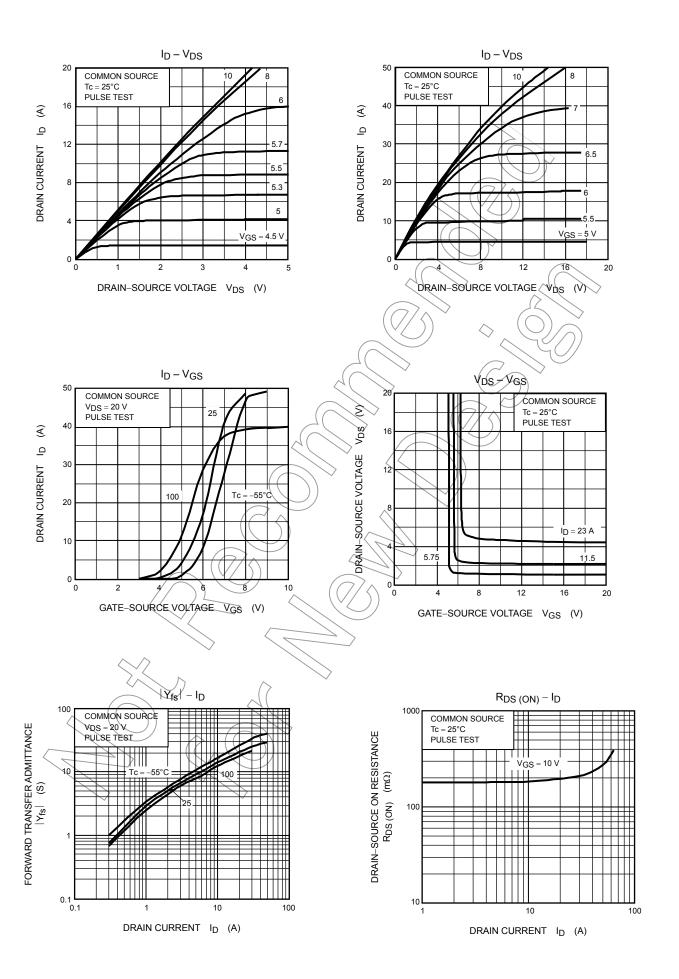
Electrical Characteristics (Ta = 25°C)

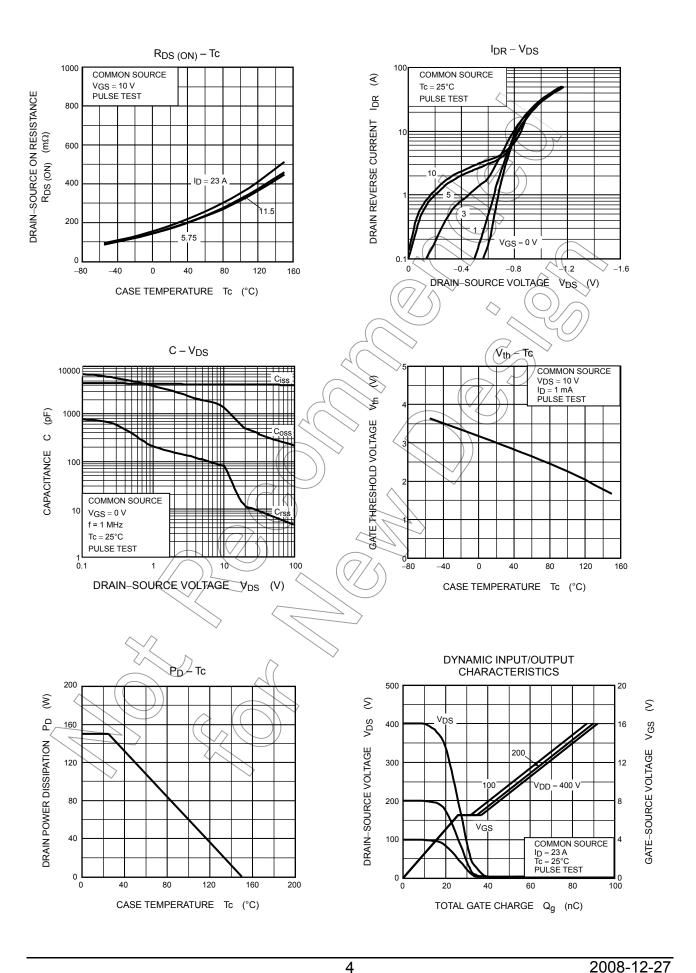
Char	acteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I _{GSS}	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Gate-source brea	akdown voltage	V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{DS} = 0 \ V$	±30	_		V
Drain cutoff curre	ent	I _{DSS}	V _{DS} = 500 V, V _{GS} = 0 V	_	_	500	μΑ
Drain-source bre	akdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	500	_		V
Gate threshold vo	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	7(4.0	V
Drain-source ON	resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 11.5 A	>~	0.18	0.23	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 11.5 A	3.4	12		S
Input capacitance	e	C _{iss}		_	4250		
Reverse transfer capacitance		C _{rss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	· —	10		pF
Output capacitance		Coss		_	420		
Switching time	Rise time	t _r	10 V I _D = 11.5 A V _{OUT} V _{GS}	-	12		
	Turn-on time	t _{on}	4.7Ω \$ R _L = \ 17.4 Ω	_((45) —	20
	Fall time	t _f	V _{DD} ≈ 200 V	7	> 10		ns
	Turn-off time	t _{off}	Duty-≤ 1%, t _W = 10 μs		80		
Total gate charge Q _g) —	60	_		
Gate-source charge Q _{gs}		Qgs	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 23 \text{ A}$		50	_	nC
Gate-drain charge Qgd		Qgd		_	10	_	

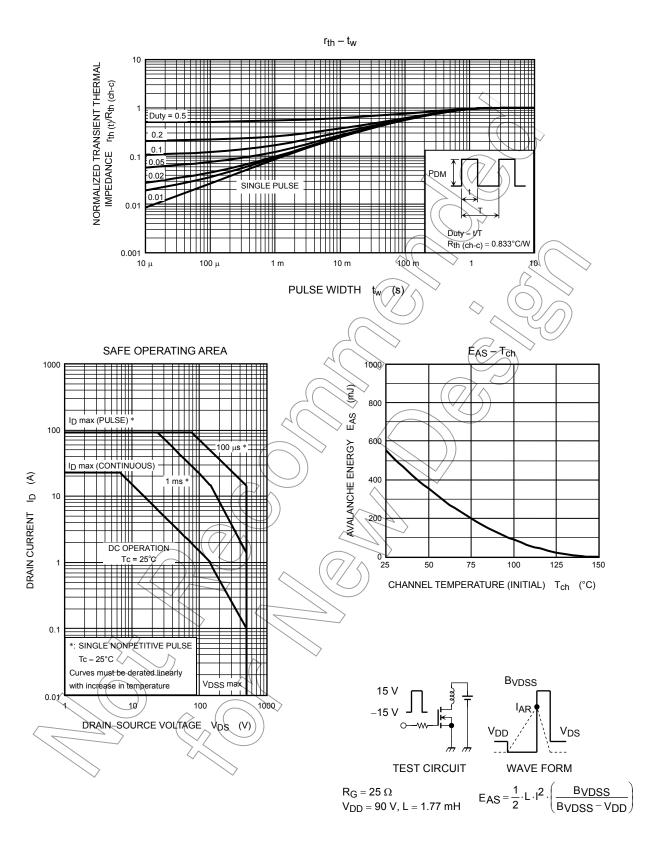
Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1))) I _{DR}		_	_	23	А
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	92	Α
Forward voltage (diode)	VDSF	$I_{DR} = 23 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 23 A, V _{GS} = 0 V,	_	1350	_	ns
Reverse recovery charge	Q _{rr}	dl _{DR} /dt = 100 A/μs	_	24	_	μС

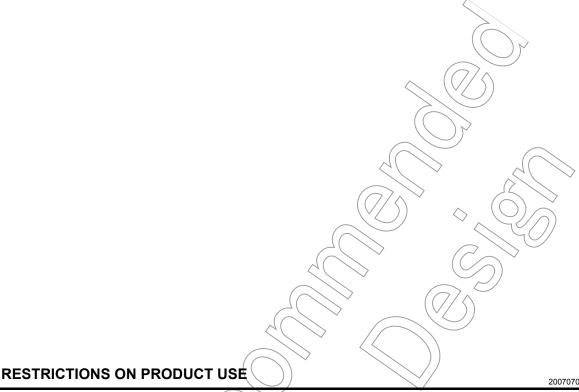








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